

16Mb (2048K x 8 Bits) LOW POWER CMOS SRAM

REVISION HISTORY

RevisionDescriptionIssue DateRev. 1.0Initial releaseFeb.25.2022

16Mb (2048K x 8 Bits) LOW POWER CMOS SRAM

FEATURES

■ Fast access time : 45ns
■ Low power consumption:
Operating current : 12mA (TYP.)
Standby current : 5µA (TYP.)

■ Single 2.7V ~ 3.6V power supply

■ All inputs and outputs TTL compatible

Fully static operationTri-state output

■ Data retention voltage : 1.5V (MIN.)

■ Package : 44-pin 400 mil TSOP-II

48-ball 6mm x 8mm TFBGA

GENERAL DESCRIPTION

The AS6C1608B is a 16,777,216-bit low power CMOS static random access memory organized as 2,097,152 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

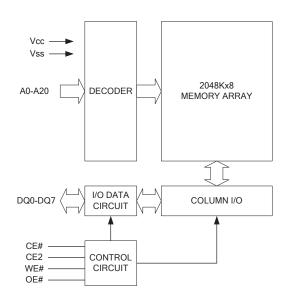
The AS6C1608B is well designed for very low power system applications, and particularly well suited for battery back-up nonvolatile memory application.

The AS6C1608B operates from a single power supply of 2.7V ~ 3.6V and all inputs and outputs are fully TTL compatible

PRODUCT FAMILY

Product	Operating	Vcc Range	Speed	Power Dissipation				
Family	Temperature	vcc Kange	Speed	Standby(IsB1,TYP.)	Operating(Icc,TYP.)			
AS6C1608B(I)	-40 ~ 85°C	2.7 ~ 3.6V	45ns	5μΑ	12mA			

FUNCTIONAL BLOCK DIAGRAM



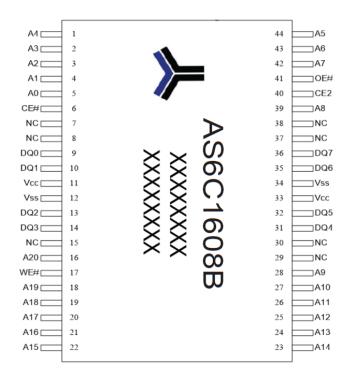
PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0 – A20	Address Inputs
DQ0 – DQ7	Data Inputs/Outputs
CE#, CE2	Chip Enable Inputs
WE#	Write Enable Input
OE#	Output Enable Input
Vcc	Power Supply
Vss	Ground
NC	No Connection

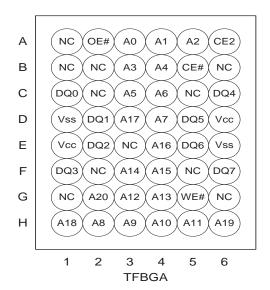


PIN CONFIGURATION

44-pin TSOP(Type II)



48-ball 6mm x 8mm TFBGA



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ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	RATING	UNIT
Voltage on Vcc relative to Vss	VT1	-0.5 to 4.6	V
Voltage on any other pin relative to Vss	VT2	-0.5 to Vcc+0.5	V
Operating Temperature	ТА	-40 to 85(I grade)	$^{\circ}\!\mathbb{C}$
Storage Temperature	Tstg	-65 to 150	°C
Power Dissipation	Po	1	W
DC Output Current	Іоит	50	mA

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	CE2	OE#	WE#	I/O OPERATION	SUPPLY CURRENT
Standby	Н	Х	Х	Х	High-Z	IsB,IsB1
Starioby	Х	L	L X X High-Z		I _{SB} ,I _{SB1}	
Output Disable	L	Н	Н	Н	High-Z	Icc,Icc1
Read	L	Н	L	Н	D _{оит}	Icc,Icc1
Write	L	Н	Х	L	Din	Icc,Icc1

Note: H = V_{IH}, L = V_{IL}, X = Don't care.



DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	I		MIN.	TYP. *4	MAX.	UNIT
Supply Voltage	Vcc		2.7	3.0	3.6	V		
Input High Voltage	V _{IH} ²¹				2.2	-	Vcc+0.3	V
Input Low Voltage	V _{IL} ²				- 0.2	ı	0.6	V
Input Leakage Current	ILI	$V_{CC} \ge V_{IN} \ge V_{SS}$			- 1	-	1	μΑ
Output Leakage Current	ILO	Vcc ≧ Vouт ≧ Vss Output Disabled			- 1	-	1	μΑ
Output High Voltage	Vон	I _{OH} = -1mA			2.2	2.7	-	V
Output Low Voltage	Vol	$I_{OL} = 2mA$			-	-	0.4	V
	Icc	Cycle time = Min. CE# = V _{IL} and CE2 = V _{II}	4	- 45	-	12	20	mA
Average Operating	100	I _{I/O} = 0mA Other pins at V _I L or V _I H		- 55	-	10	18	mA
Power supply Current	Icc ₁	Cycle time = 1μ s CE# \leq 0.2V and CE2 \geq Vcc-0.2V I _{VO} = 0mA Other pins at 0.2V or Vcc-0.2V			1	3	5	mA
	I _{SB}	CE# = V _{IH} or CE2 = V _{IL} Other pins at V _{IL} or V _{IH}			ı	0.3	2	mA
Standby Power Supply Current	I _{SB1}	CE# \ge V _{CC} -0.2V or CE2 \le 0.2V	25 ℃	*5	-	5	10	μΑ
Notes	1361	Other pins at 0.2V or Vcc-0.2V			-	5	20	μΑ

Notes:

- 1. $V_{IH}(max) = V_{CC} + 2.0V$ for pulse width less than 6ns.
- 2. VIL(min) = Vss 2.0V for pulse width less than 6ns.
- 3. Over/Undershoot specifications are characterized on engineering evaluation stage, not for mass production test.
- 4. Typical values are included for reference only and are not guaranteed or tested.
 - Typical valued are measured at Vcc = Vcc(TYP.) and Ta = 25° C
- 5. This parameter is measured at VCC = 3.0V

CAPACITANCE (TA = 25°C pF = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	6	pF
Input/Output Capacitance	C _{I/O}	-	8	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0.2V to Vcc - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L = 30pF + 1TTL$, $I_{OH}/I_{OL} = -1mA/2mA$



AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM.	AS6C16	AS6C1608B-45		55ns Specification	
		MIN.	MAX.	MIN.	MAX.	UNIT
Read Cycle Time	trc	45	-	55	-	ns
Address Access Time	taa	-	45	-	55	ns
Chip Enable Access Time	tace	-	45	-	55	ns
Output Enable Access Time	toe	-	25	-	30	ns
Chip Enable to Output in Low-Z	tcLz*	10	-	10	-	ns
Output Enable to Output in Low-Z	tolz*	5	-	5	-	ns
Chip Disable to Output in High-Z	tcHz*	-	15	-	20	ns
Output Disable to Output in High-Z	tonz*	-	15	-	20	ns
Output Hold from Address Change	tон	10	-	10	-	ns

(2) WRITE CYCLE

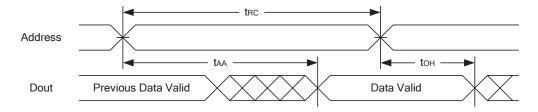
PARAMETER	SYM.	AS6C1	AS6C1608B-45 55ns Spe		55ns Specification	
		MIN.	MAX.	MIN.	MAX.	UNIT
Write Cycle Time	twc	45	-	55	-	ns
Address Valid to End of Write	t _{AW}	40	-	50	-	ns
Chip Enable to End of Write	tcw	40	-	50	-	ns
Address Set-up Time	tas	0	-	0	-	ns
Write Pulse Width	twp	35	-	45	-	ns
Write Recovery Time	twr	0	-	0	-	ns
Data to Write Time Overlap	tow	20	-	25	-	ns
Data Hold from End of Write Time	tdh	0	-	0	-	ns
Output Active from End of Write	tow*	5	-	5	-	ns
Write to Output in High-Z	twnz*	-	15	-	20	ns

^{*}These parameters are guaranteed by device characterization, but not production tested.

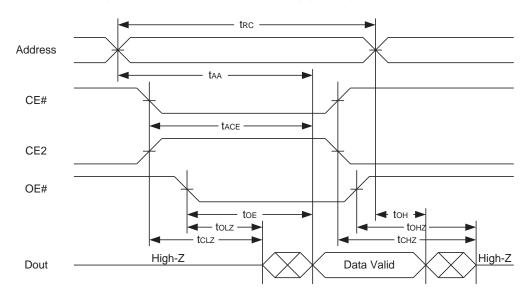


TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



READ CYCLE 2 (CE# and CE2 and OE# Controlled) (1,3,4,5)

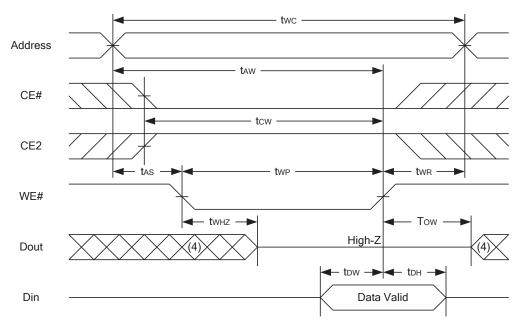


Notes:

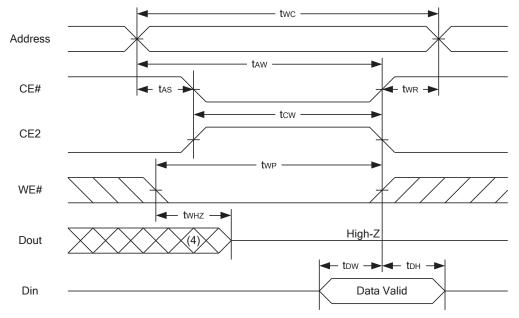
- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low., CE2 = high.
- 3.Address must be valid prior to or coincident with CE# = low, CE2 = high; otherwise tAA is the limiting parameter.
- 4.tclz, tolz, tolz and tolz are specified with Cl = 5pF. Transition is measured $\pm 500mV$ from steady state.
- 5.At any given temperature and voltage condition, tcHz is less than tcLz , t_{OHZ} is less than toLz.



WRITE CYCLE 1 (WE# Controlled) (1,2,4,5)



WRITE CYCLE 2 (CE# and CE2 Controlled) (1,4,5)



Notes:

- 1.A write occurs during the overlap of a low CE#, high CE2, low WE#.
- 2.During a WE# controlled write cycle with OE# low, tWP must be greater than tWHZ + tDW to allow the drivers to turn off and data to be placed on the bus.
- 3. During this period, I/O pins are in the output state, and input signals must not be applied.
- 4.If the CE# low transition and CE2 high transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- 5.tOW and tWHZ are specified with CL = 5pF. Transition is measured ±500mV from steady state.



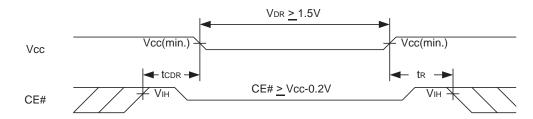
DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Vcc for Data Retention	V _{DR}	$CE# \ge V_{CC} - 0.2V$ or $CE2 \le 0.2V$	1.5	-	3.6	V	
Data Retention Current		Vcc = 1.2V CE# ≧Vcc-0.2V or CE2 ≦ 0.2V	40 ℃	1	4	10	μΑ
Data Retention Current		Other pins at 0.2V or Vcc-0.2V	-40 C~ 85℃	-	4	40	μΑ
Chip Disable to Data Retention Time	tonp.	See Data Retention Waveforms (below)		0	-	-	ns
Recovery Time	t _R			tRC∗	-	-	ns

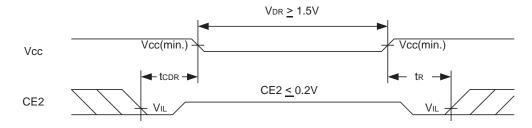
t_{RC*} = Read Cycle Time

DATA RETENTION WAVEFORM

Low Vcc Data Retention Waveform (1) (CE# controlled)



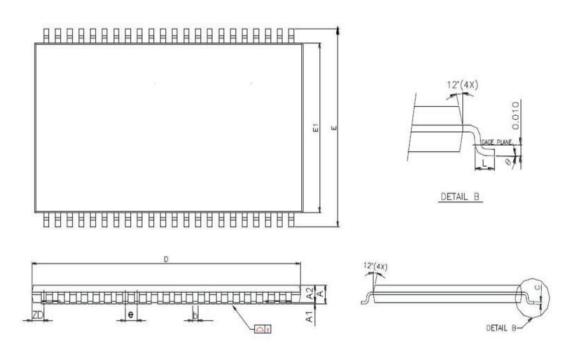
Low Vcc Data Retention Waveform (2) (CE2 controlled)





PACKAGE OUTLINE DIMENSION

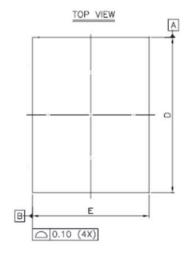
44-pin 400mil TSOP-II Package Outline Dimension

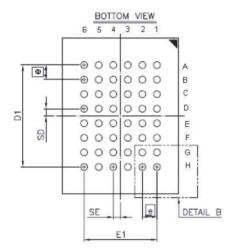


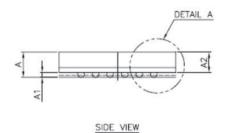
SYMBOLS	DIMENSI	ONS IN MILL	METERS	DIMENSIONS IN MILS			
STIVIBULS	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
А	-	-	1.20	-	-	47.2	
A1	0.05	0.10	0.15	2.0	3.9	5.9	
A2	0.95	1.00	1.05	37.4	39.4	41.3	
b	0.30	-	0.45	11.8	-	17.7	
С	0.12	-	0.21	4.7	-	8.3	
D	18.212	18.415	18.618	717	725	733	
E	11.506	11.760	12.014	453	463	473	
E1	9.957	10.160	10.363	392	400	408	
е	-	0.800	-	-	31.5	-	
L	0.40	0.50	0.60	15.7	19.7	23.6	
ZD	-	0.805	-	-	31.7	-	
У	-	-	0.076	-	-	3	
θ	0°	3°	6°	0°	3°	6°	

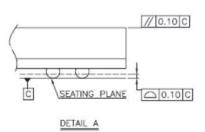
16Mb (2048K x 8 Bits) LOW POWER CMOS SRAM

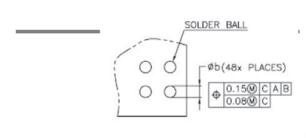
48-ball 6mm × 8mm TFBGA Package Outline Dimension











DETAIL B

6344	D	IMENSIO (mm)	N	DIMENSION (inch)			
SYM.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	_	_	1.40	_	_	0.055	
A1	0.20	0.25	0.30	0.008	0.010	0.012	
A2	_	_	1.05	_	_	0.041	
b	0.30	0.35	0.40	0.012	0.014	0.016	
D	7.95	8.00	8.05	0.313	0.315	0.317	
D1	5	.25 BS0)	0.207 BSC			
Ε	5.95	6.00	6.05	0.234	0.236	0.238	
E1	3	.75 BS0)	0	.148 BS	SC	
SE	0	.375 TY	P	0.015 TYP			
SD	0.375 TYP			0.015 TYP			
e	0	.75 BS0)	0.030 BSC			

NOTE:

- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. REFERENCE DOCUMENT : JEDEC MO-207.



16Mb (2048K x 8 Bits) LOW POWER CMOS SRAM

ORDERING INFORMATION

Alliance Part no	Organisation	Vcc Range	Package	Operating Temp	Speed ns
AS6C1608B-45BIN - Tray	2048K x 8	2.7V – 3.6V	48-ball 6mm x 8mm TFBGA	-40°C~85°C	45
AS6C1608B-45BINTR – Tape & Reel	2048K x 8	2.7V – 3.6V	48-ball 6mm x 8mm TFBGA	-40°C~85°C	45
AS6C1608B-45TIN – Tray	2048K x 8	2.7V – 3.6V	44-pin 400mil TSOP-II	-40°C~85°C	45
AS6C1608B-45TINTR – Tape & Reel	2048K x 8	2.7V – 3.6V	44-pin 400mil TSOP-II	-40°C~85°C	45

PART NUMBERING SYSTEM

AS6C	1608B	- 45	B or T	T	N
LOW POWER SRAM PREFIX	DEVICE NUMBER 16 = 16M 08 = by 8 B = Die rev.B	Access Time 45 = 45ns	B = 48ball TFBGA (6mm x 8mm) Or T = 44-pin 400mil TSOP-II	Temperature range: I = Industrial (-40°C to 85°C)	N = Lead Free ROHS Compliant Part



16Mb (2048K x 8 Bits) LOW POWER CMOS SRAM



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